

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	09/686,275	LEVENBERG, GARY
	Examiner Binh-An D. Nguyen	Art Unit 3713

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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-4,568,080	02-1986	Yokoi, Gunpei	463/34
B	US-4,575,591	03-1986	Lugaresi, Thomas J.	200/6A
C	US-4,786,768	11-1988	Langewis et al.	200/6A
D	US-D320,018	09-1991	Bakanowsky, III, Louis J.	D14/172
E	US-5,091,832 A	02-1992	Tortola et al.	362/109
F	US-5,213,327 A	05-1993	Kitaue, Kazumi	463/38
G	US-D336,665	06-1993	Tugendhaft, Majer	D21/329
H	US-5,213,335 A	05-1993	Dote et al.	463/51
I	US-5,312,114 A	05-1994	Lipson, Warren M.	434/236
J	US-5,464,214 A	11-1995	Griffin, Tom	273/148B
K	US-D370,501	06-1996	Raviv et al.	D14/401
L	US-D377,057	12-1996	Lee, Lan-Yan	D14/401
M	US-5,615,083 A	03-1997	Burnett, Robert J.	361/686

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
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**NON-PATENT DOCUMENTS**

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U	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,685,776	11-1997	Stambolic et al.	463/46
	B	US-5,766,077	06-1998	Hongo, Takeichi	463/30
	C	US-D397,729	09-1998	Schulz et al.	D21/324
	D	US-D399,268	10-1998	Liu, Da-Ming	D21/333
	E	US-D401,629	11-1998	Wing, Yu Wah	D21/329
	F	US-5,855,483 A	01-1999	Collins et al.	434/322
	G	US-5,883,690 A	03-1999	Meyers et al.	345/161
	H	US-5,967,898 A	10-1999	Takasaka et al.	463/37
	I	US-5,976,018 A	11-1999	Druckman, Gil	463/47
	J	US-6,083,104 A	07-2000	Choi, Kei Fung	463/6
	K	US-6,086,478 A	07-2000	Klitsner et al.	463/35
	L	US-6,159,101 A	12-2000	Simpson, Mark Christopher	463/46
	M	US-6,193,609 B1	02-2001	D'Achard Van Enschut, Johannes F. M.	463/37

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
	T					

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,200,219 B1	03-2001	Rudell et al.	463/37
	B	US-6,210,278 B1	04-2001	Klitsner, Daniel B.	463/35
	C	US-6,209,845 B1	04-2001	Klitsner et al.	248/694
	D	US-6,290,565 B1	09-2001	Galyean III et al.	446/99
	E	US-6,322,449 B1	11-2001	Klitsner et al.	463/37
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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